

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/699,766	SUN ET AL.	
Examiner	Art Unit	
Chase Peers	2186	

	SEAR	CHED	
Class	Subclass	Date	Examiner
711	103	12/27/2005	СР
713	1	12/27/2005	СР
717	178	12/27/2005	СР
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Searched EAST database for systems on a chip and like terms	12/21/2005	СР